


<b>Search Notes</b>  	<b>Application/Control No.</b>  10595766	<b>Applicant(s)/Patent Under Reexamination</b>  BEYER ET AL.
	<b>Examiner</b>  CECILIA M JAISLE	<b>Art Unit</b>  1624

SEARCHED			
Class	Subclass	Date	Examiner
514	264.11	1/15/2008	C. Jaisle
544	270	1/15/2008	C. Jaisle
514	264.11	5/19/2008	C. Jaisle
544	270	5/19/2008	C. Jaisle

SEARCH NOTES		
Search Notes	Date	Examiner
STN &^ Inventor Names searched by STIC	1/15/2008	C. Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
514	264.11	5/19/2008	C. Jaisle
544	270	5/19/2008	C. Jaisle